g	GE I	Energy	Functional Testing Specification
	Parts & Repair Services Louisville, KY		LOU-ATE1-DS3800HSQD/E

Test procedure for a DS3800HSQD/E

DOCUMENT REVISION STATUS: Determined by the last entry in the "REV" and "DATE" column

REV.	DESCRIPTION	SIGNATURE	REV. DATE
Α	Initial release	Eric Rouse	10/25/2001
В	Transferred procedure from a general group to a specific single document. Also added asset numbers to section 5.	Jeffrey Barton	8/25/2010
С	Added section 6.3 to functionally test the card	Jeffrey Barton	6/27/2012

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DATE 10/25/2001	DATE 8/25/2010	DATE	DATE 8/25/2010

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Functional test procedure for an ATE tested item.

1. SCOPE

1.1 This is a functional test procedure for DS3800HSQD/E cards that are to be tested on ATF1

2. STANDARDS OF QUALITY

2.1 Refer to the current revision of the IPC-A-610 standard for workmanship standards.

3. APPLICABLE DOCUMENTS

- **3.1** The following document(s) shall form part of this specification to the extent specified herein. Unless otherwise indicated, the latest issue shall apply.
 - **3.1.1** Check board's electronic folder for more information

4. **ENGINEERING REQUIREMENTS**

- 4.1 Equipment Cleaning
 - **4.1.1** Equipment should be clean and free of debris prior to applying power unless performing an initial check. Refer to site specific SRA's for cleaning guidelines.
- 4.2 Equipment Inspection
 - **4.2.1** Equipment should be visually inspected for any defects prior to applying power. This inspection should include the following as a minimum:
 - 4.2.1.1 Wires broken or cracked
 - 4.2.1.2 Terminal strips / connectors broken or cracked
 - **4.2.1.3** Loose wires
 - 4.2.1.4 Components visually damaged
 - 4.2.1.5 Capacitors leaking
 - 4.2.1.6 Solder joints damaged or cold
 - 4.2.1.7 Circuit board burned or de-laminated
 - 4.2.1.8 Printed wire runs burned or damaged

5. EQUIPMENT REQUIRED

5.1 The following equipment is required to perform the process requirements. Equipment may be substituted provided that all accuracy's and test ratios are equivalent or better.

Qty	Reference #	Description
1	H033779	ATE1
1	H188939	DS3800HSQD/E Wiring Harness
1		DS3800DSQD LED Card
1	H033662	Analog Siltron Drive

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6. TESTING PROCESS

- 6.1 Setup
 - **6.1.1** As required by ATE instructions
- 6.2 Testing Procedure
 - **6.2.1** Identify the test to be used on the ATE by matching the model number with the ones on the system and follow the instructions given after execution.
- 6.3 Functional Test
 - **6.3.1** Once unit has passed through the ATE test, install card into Analog Siltron Drive and functionally exercise.
 - **6.3.1.1** Power Up
 - **6.3.1.2** Watch boot up sequence complete (LEDs)
 - 6.3.1.3 Clear Faults (push reset)
 - **6.3.1.4** With the Speed Control Pot verify that unit runs in both directions, forward and reverse.
 - **6.3.1.5** Center speed reference Pot.
 - **6.3.1.6** Power Down
 - 6.3.1.7 Remove UUT and re-install master board.
- 6.4 ***TEST COMPLETE ***

7. NOTES

7.1 Changes to the electronic ATE test are recorded in the Software Control Database

8. Attachments

8.1 None at this time.